

Notice of References Cited	Application/Control No. 10/665,713		Applicant(s)/Patent Under Reexamination DUPUIS ET AL	
	Examiner A. Sefer		Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,388,307	05-2002	Kondo et al.	257/592
	B	US-5,821,149	10-1998	Schuppen et al.	438/312
	C	US-6,352,907	03-2002	Gris, Yvon	438/438
	D	US-6,509,242	01-2003	Frei et al.	438/312
	E	US-6,417,058	07-2002	Richardson et al.	438/312
	F	US-5,962,880	10-1999	Oda et al.	257/198
	G	US-5,846,869	12-1998	Hashimoto et al.	438/365
	H	US-5,633,179	05-1997	Kamins et al.	438/318
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE 19652423 /	06-1998	Germany	Heinemann et al	
	O	KR 2001-009810 /	07-1999	Korea	choi et al	
	P	JP 6-69434 /	03-1994	Japan	Naruse et al	
	Q	JP 61-230374 /	10-1986	Japan	Oshima et al	
	R	JP 61-31387	02-1986	Japan	Kitajima	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.